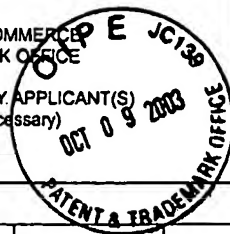


FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 03500.010106.5		APPLICATION NO. 10/615,995	
			APPLICANT Toshikazu Ohnishi et al.			
			FILING DATE July 10, 2003		GROUP 2879 NYA	
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JW	6,147,449	11/14/00	Iwasaki et al.	313	495	
JW	6,171,162 B1	01/09/01	Iwasaki et al.	445	6	
JW	6,169,356 B1	01/02/01	Ohnishi et al.	313	495	
JW	6,184,610 B1	02/06/01	Shibata et al.	313	309	
JW	6,246,168 B1	06/12/01	Kishi et al.	313	495	
JW	6,384,541 B1	05/07/02	Ohnishi et al.	315	169.3	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
JW	1069826 A	3/10/93	China	H01J	1/30	Abst. & Trans.
JW	1069828 A	3/10/93	China	H01J	19/42	Abst., Trans. & EP 0 513 777
JW	1-031332	02/01/89	Japan	H01J	29/48	Abst.
JW	0 513 777 A2	11/19/92	EPO	H01J	1/30	English
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER Joseph Williams			DATE CONSIDERED 3/3/04			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.010106.5		APPLICATION NO. <u>10/615995</u> NOT YET ASSIGNED	
				APPLICANT TOSHIKAZU OHNISHI ET AL.			
				FILING DATE FILED HEREWITH		GROUP 2879	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>JW</i>		6,348,761 B1	2/02	Nomura et al.	313	495	6/94
<i>JW</i>		4,949,019	8/90	Isaka et al.	445	6	
<i>JW</i>		5,066,883	11/91	Yoshioka et al.	313	309	
<i>JW</i>		5,006,883	11/91	Yoshioka et al.	313	309	
<i>JW</i>		4,954,744	9/90	Suzuki et al.	313	336X	
<i>JW</i>		5,285,129	2/94	Takeda et al.	313	309X	
<i>JW</i>		5,256,936	10/93	Itoh et al.	313	309X	
<i>JW</i>		5,141,460	8/92	Jaskie et al.	313	309X	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
<i>JW</i>		0523702A1	1/93	EPO			Abstract
<i>JW</i>		1283749A	11/89	JAPAN			Abstract
<i>JW</i>		A1309242	12/89	JAPAN			No
<i>JW</i>		536731A1	4/93	EPO			
<i>JW</i>		1-309242	12/89	JAPAN			Translation
<i>JW</i>		0 299 461	1/89	EPO			
EXAMINER <u>Joseph Williams</u>				DATE CONSIDERED <u>3/3/04</u>			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		ATTY DOCKET NO. 03500.010106.5	APPLICATION NO. <u>10/615495</u> NOT YET ASSIGNED
APPLICANT TOSHIKAZU OHNISHI ET AL.		FILING DATE FILED HEREWITH	
GROUP 2879			

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
<i>JW</i>	"Metal Influence on Switching MIM Diodes", H. Pagnia, et al., Phys. Stat. Sol. (a), 111, 387 (1989)
<i>JW</i>	"Scanning Tunnelling Microscopic Investigations of Electroformed Planar Metal-Insulator-Metal Diodes," H. Pagnia, N. Sotnik and W. Wirth, Int. J. Electronics, Vol. 69, No. 1, 25-32 (1990)
<i>JW</i>	"Energy Distribution of Emitted Electrons from Electroformed MIM Structures: The Carbon Island Model," M. Bischoff, H. Pagnia and J. Trickl, Int. J. Electronics, Vol. 73, No. 5, 1009-1010 (1992)
<i>JW</i>	"Thin Film Handbook," Committee 131 of Japanese Society for the Promotion of Art and Science
<i>JW</i>	"On the Electron Emission from Evaporated Thin Au Films," M. Bischoff, R. Holzer and H. Pagnia, Physics Letters, Vol. 62A, No. 7 (October 3, 1977)
<i>JW</i>	"The Electroforming Process in MIM Diodes," Vol. 85, R. Blessing, H. Pagnia and N. Sotnik, Thin Solid Films, 119-128 (1981)
<i>JW</i>	"Evidence for the Contribution of an Adsorbate to the Voltage-Controlled Negative Resistance of Gold Island Film Diodes," R. Blessing, H. Pagnia and R. Schmitt, Thin Solid Films, Vol. 78, 397-401 (1981)
<i>JW</i>	"Water-Influenced Switching in Discontinuous Au Film Diodes," R. Muller and H. Pagnia, Materials Letters, Vol. 2, No. 4A, 283-285 (March 1984)
<i>JW</i>	"Influence of Organic Molecules on the Current-Voltage Characteristic of Planar MIM Diodes," H. Pagnia, N. Sotnik and H. Strauss, Phy. Stat. Sol., Vol. 90, 771-778 (1985)
<i>JW</i>	"Influence of Gas Composition on Regeneration in Metal/Insulator/Metal Diodes," M. Borbonus, H. Pagnia and N. Sotnik, Thin Solid Films, Vol. 151, 333-342 (1987)
<i>JW</i>	"Prospects for Metal/Non-Metal Microsystems: Sensors, Sources and Switches," H. Pagnia, Int. J. Electronics, Vol. 73, No. 5, 319-825 (1992)
<i>JW</i>	W.P. Dyke, et al., "Field Emission," Advances in Electronics and Electron Physics, 1956, pp. 90-185
<i>JW</i>	C.A. Spindt, et al. "Physical Properties of Thin-Film Field Emission Cathodes With Molybdenum Cones," J. Appl. Phys., Vol. 47 (1976) pp. 5248-5263
<i>JW</i>	C.A. Mead, "Operation of Tunnel-Emission Devices," J. Appl. Phys., Vol. 32, (1961) pp. 646-652

EXAMINER <u>Joseph Williams</u>	DATE CONSIDERED <u>3/3/04</u>
---------------------------------	-------------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		ATTY DOCKET NO. 03500.010106.5	APPLICATION NO. <u>10/615995</u> NOT YET ASSIGNED
APPLICANT TOSHIKAZU OHNISHI ET AL.		FILING DATE FILED HEREWITH	
GROUP 2879			
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)			
An		M.I. Elinson "The Emission of Hot Electrons and the Field Emission of Electrons from Tin Oxide," Radio Engineering and Electronic Physics, (1965), pp. 1290-1296	
An		G. Dittner, "Electrical Conduction and Electron Emission of Discontinuous Thin Films," Thin Solid Films, 9, (1972) pp. 317-328	
An		H. Hartwell, et al, "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films," Int'l Electron Devices Meeting (1975) pp. 519-521	
An		M. Araki, "Electroforming and Electron Emission of Carbon Thin Films," J. Vac. Soc. Japan, 26, (1983) pp. 22-29	
An		"Carbon-Nanoslit Model for the Electroforming Process in MIM Structures," M. Bischoff, Int. J. Electronics, Vol. 70, No. 3, 491-498 (1991)	
An		Patent Abstracts of Japan, vol. 14, no. 1 08 (E-896) (4051), Feb 27, 1990	
EXAMINER		DATE CONSIDERED <u>3/3/04</u>	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 3 of 3